

CIRQULAIR MEASUREMENT WITH TSI CPC AND SMPS

22-May-2018

TO

Peter van Wees

FROM

Jan Troost

Effectiveness measurement of the Cirqulair at office j.j. bos b.v. (TSI distributor for Benelux countries) in Gouda, NL

USED EQUIPMENT AND SETTINGS:

AIM Version; 10.2

Classifier Model;3082;Classifier S/N;3082001714002;Classifier Firmware Version;2.1

Neutralizer Model;3088;Neutralizer S/N;3088011613003

Impactor (cm);0.0710;Impactor S/N;7100490

DMA Model;3085;DMA S/N;3085A1748001

DMA Inner Radius (cm);0,937

DMA Outer Radius (cm);1,905

DMA Characteristic Length (cm);4,987

HV Polarity; NEG

Detector Model;3787;Detector S/N;3787111703

Detector Sample Flow (L/min);0,60; Detector Inlet Flow (L/min);0,60

Reference Gas Viscosity (Pa*s);1,832450e-005

Reference Mean Free Path (m);6,730000e-008

Reference Gas Temperature (K);296,15

Reference Gas Pressure (kPa);101,30

Sutherland Constant (K);110,40

Tube Length (cm);29,00

Tube Diameter (cm);0,48

Channels/Decade;64

Multiple Charge Correction; TRUE

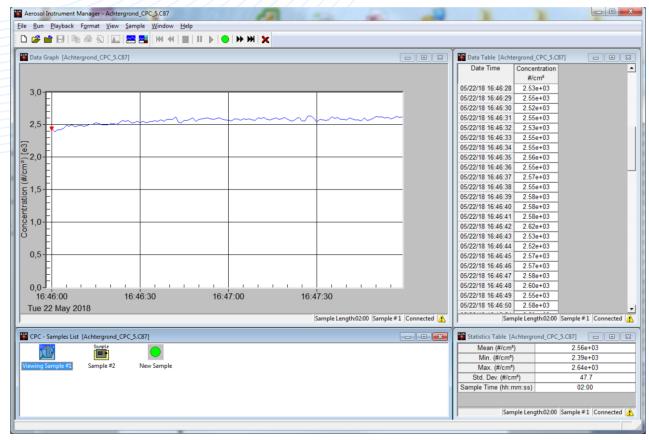
Nanoparticle Agglomerate Mobility Analysis; FALSE

Diffusion Correction; TRUE

A. Total concentration measurement by CPC (3787) only with a starting point (D50) of 5 nm.:

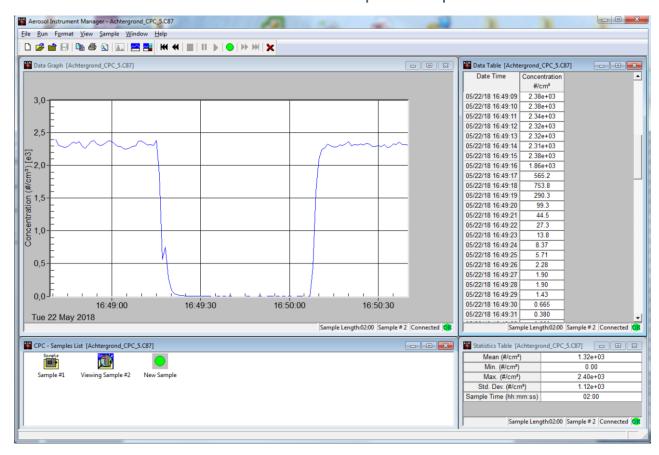
1) Background measurement (Cirqulair = Off).





Conc: 2.6E3 part/cm3

2) Measurement at Inlet and Outlet of the Cirqulair (Cirqulair = On).

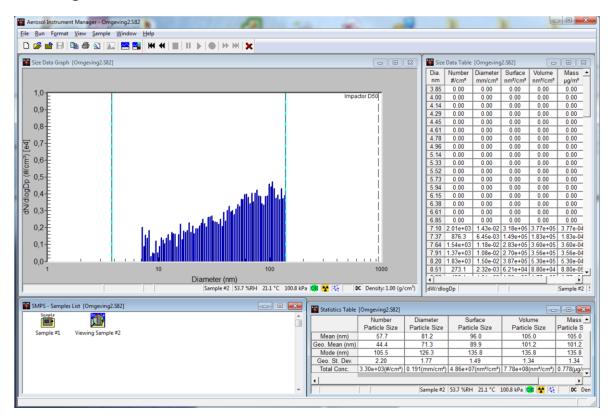


Conc: Jump from 2.6E3 part/cm3 at Inlet to 1 to 5 part/cm3 at Outlet and viva versa



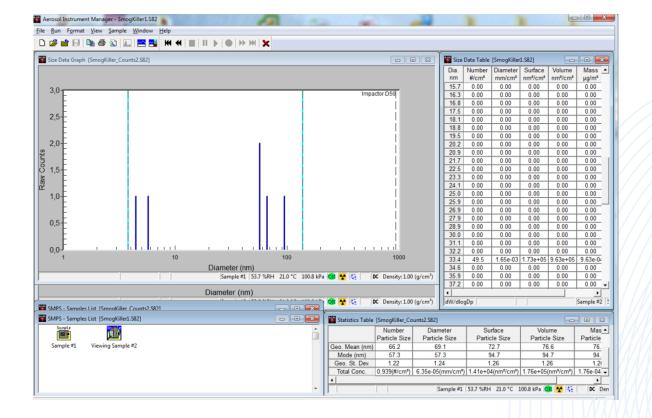
B. Concentration measurement per Size bin by SMPS(3938N87) over size range [5 - 150 nm.] determined by used nano-DMA and CPC model:

1) Background



Total conc. from 5nm up to 140 nm, (determined by SMPS settings): 3.3E3 part/cm3

2) At Outlet of the Cirqulair



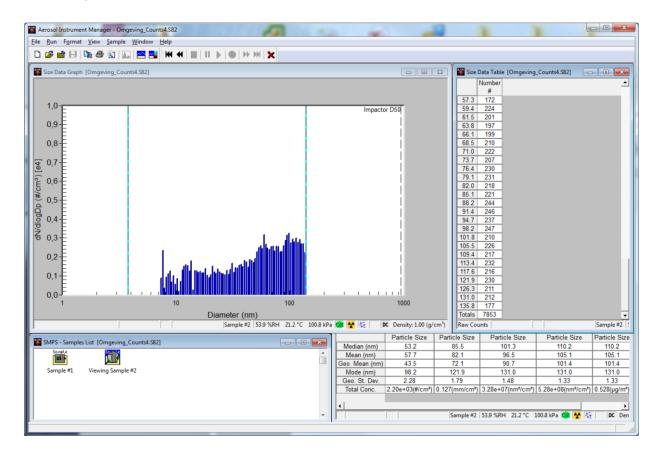


Total conc. from 5nm up to 140 nm, (determined by SMPS settings): 3.3E3 part/cm3

C. Raw particle counts per Size bin by SMPS(3938N87) over size range [5 - 150 nm.]

determined by used nano-DMA and CPC model:

1) Background

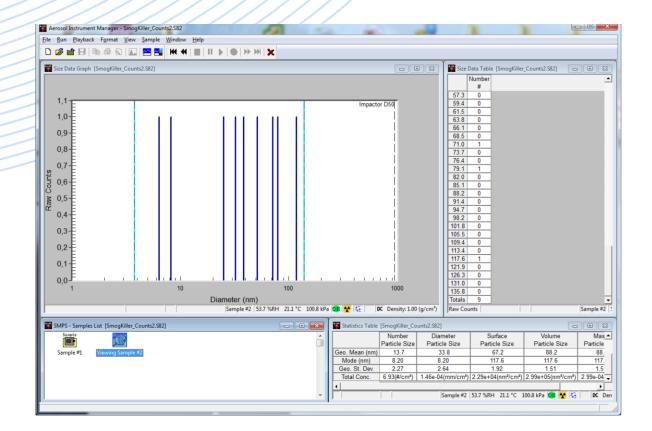


Total counts from 5nm up to 140 nm, (determined by SMPS settings) during 100 sec.

Scan time: 78533

2) At Outlet of the Cirqulair





Total counts from 5nm up to 140 nm, (determined by SMPS settings) during 100 sec. Scan time: varying in 2 samples from 6 (to 9 counts

conclusion:

The Cirqulair proves to be very effective in removing (nano) particles in size range up to 10 μ m as shown by CPC measurement 1 and in range of 5 to 140 nm. as indicated by SMPS measurement 2 and 3

Kind regards,

Jan Troost

Product Specialist TSI Particle Instruments j.j. bos b.v.

Note:

CPC = Condensation Particle Counter (in this case water based) SMPS = Scanning

Mobility Particle Sizer

DMA = Differential Mobility Analyzer

